

Search Notes

Application/Control No.

09/745,606

Examiner

Annan Q. Shang

Applicant(s)/Patent under
Reexamination

NISHIKAWA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
725	38-61	10/25/2005	A.S.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR